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Aula 4, Facultad de Ciencias (Física)
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Lección inaugural del Máster NANOMAT

Applications of the dual beam (FIB-SEM) in Materials Science, Semiconductor Industry, Nanotechnology and Quantum Technologies

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In this NANOMAT introductory lecture, I will first describe the dual beam equipment, which mainly consists of a Focused Ion Beam (FIB) and a Scanning Electron Microscope (SEM) and represents a key instrument in various disciplines of research and technology. In particular, I will describe the applications of the dual beam equipment in the following fields: Materials Science, Semiconductor Industry, Nanotechnology and Quantum Technologies. Most of the examples provided in the lecture correspond to results obtained in the last 20 years by the research groups that use the dual beam equipments existing in Zaragoza, as well as to the broad service that the Laboratory of Advanced Microscopies (LMA, Universidad de Zaragoza) has given to national and foreign companies along this time.

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